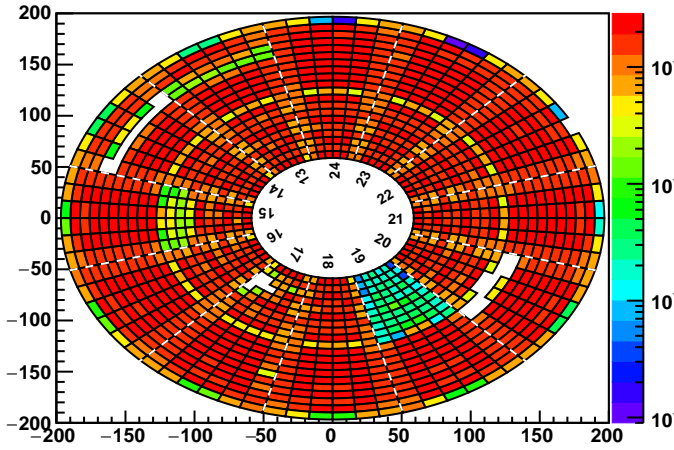
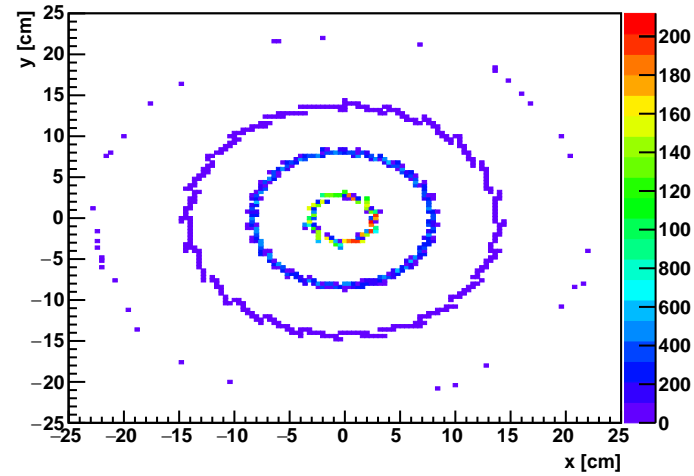


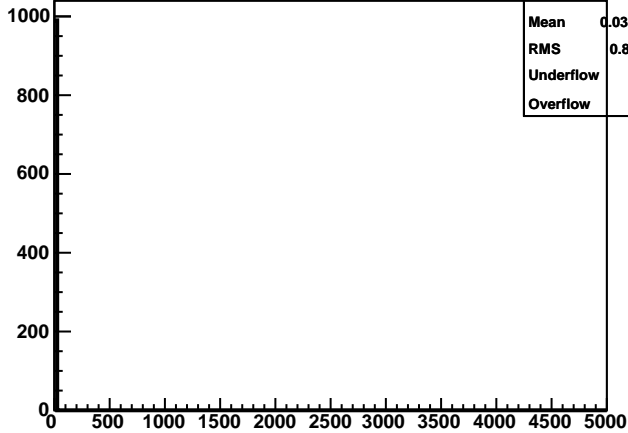
StE point: r-phi distribution of charge, tpcE



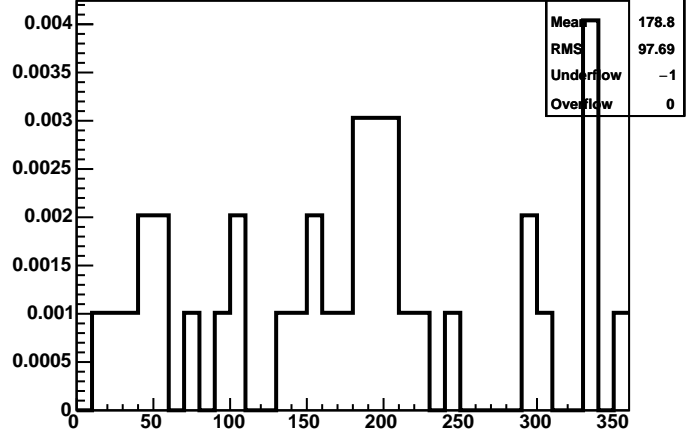
PIXEL, IST, SSD: Distribution of hits in XY



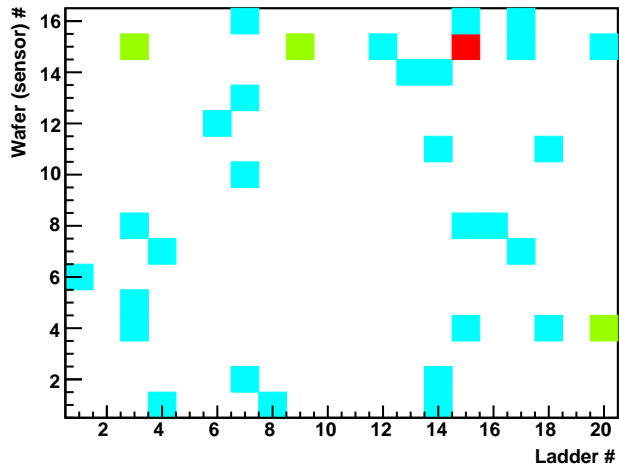
StE point: # hits sst



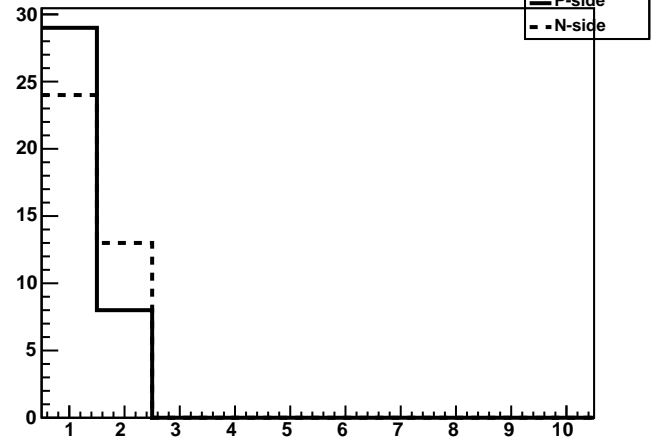
StE SST: ϕ of hits (per event)



StE SST: wafer id vs ladder id (per event)

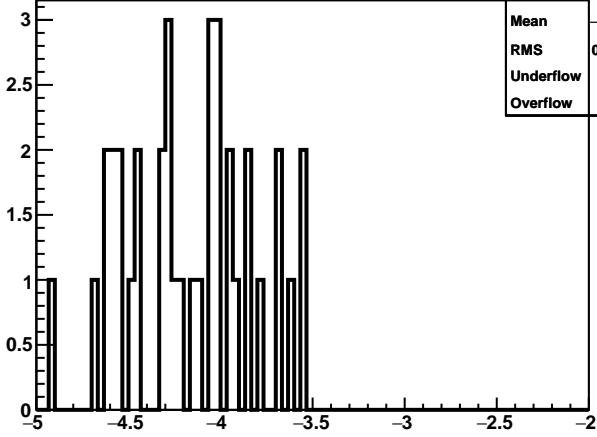


StE SST: size of clusters



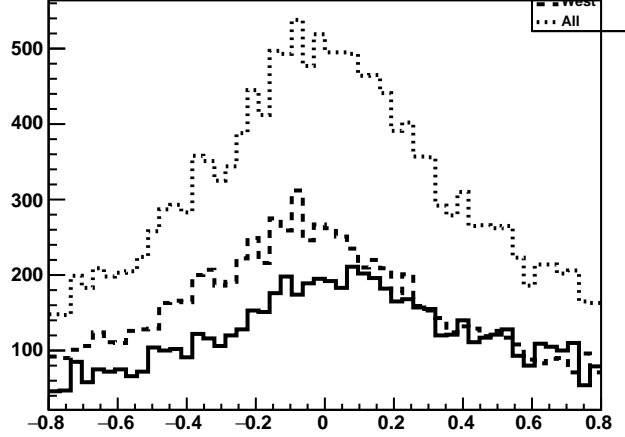
StE SST: log10(energy) of hits

StEQaPointESST	
Entries	37
Mean	-4.169
RMS	0.3427
Underflow	0
Overflow	0



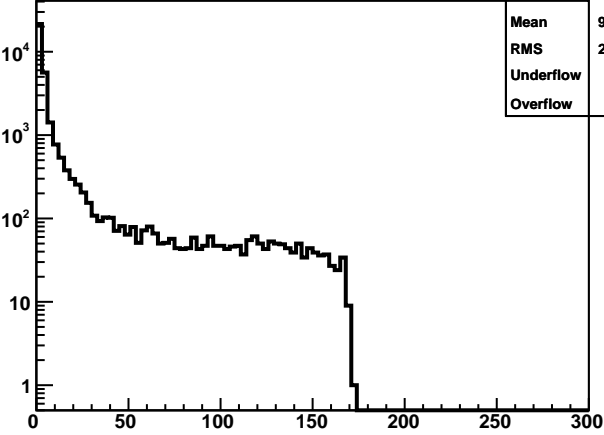
StE globtrk: signed impact param from prim vtx, tpc

Legend	
—	East
- - -	West
...	All



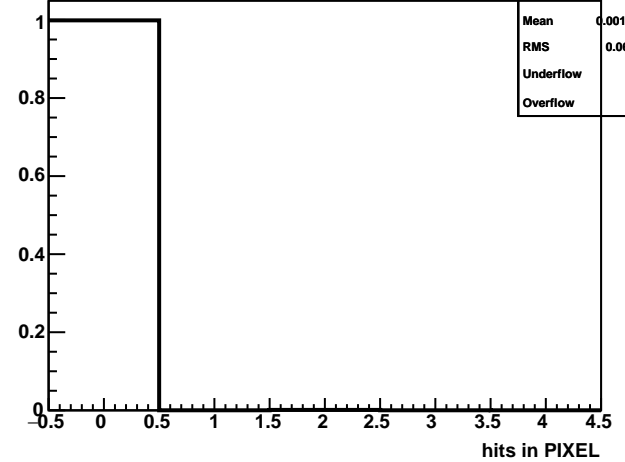
StE globtrk: impact param from prim vtx, tpc

StEQaGrkImpactrT	
Entries	33674
Mean	9.543
RMS	25.27
Underflow	0
Overflow	0



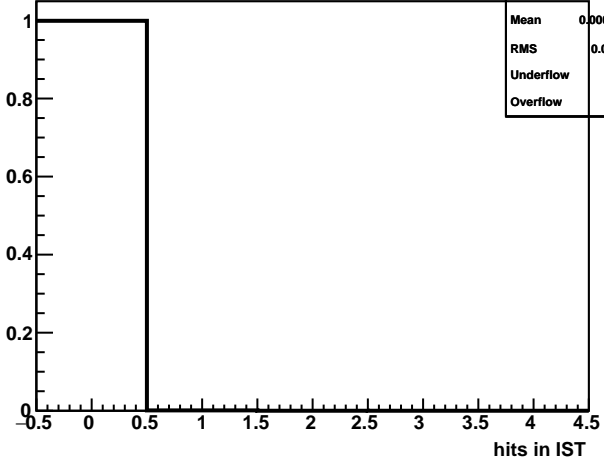
StE PIXEL: Hits per global track

StEQaGrkPxIHit	
Entries	449597
Mean	0.001964
RMS	0.06291
Underflow	-1
Overflow	0



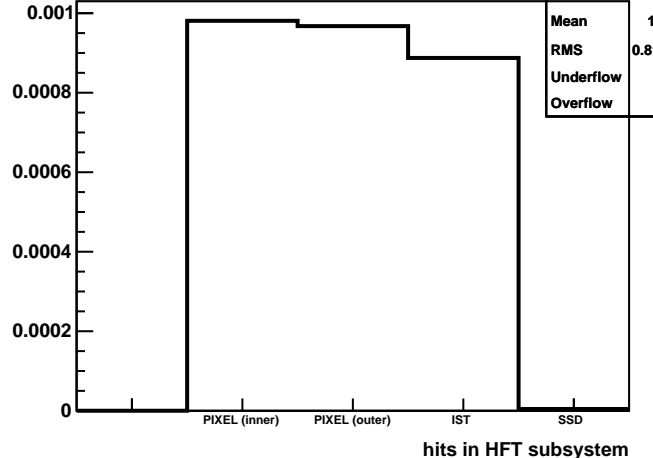
StE IST: Hits per global track

StEQaGrkIstHit	
Entries	449597
Mean	0.0008875
RMS	0.02993
Underflow	-1
Overflow	0

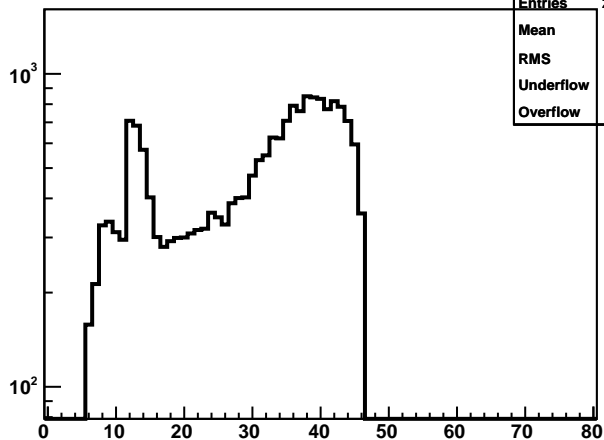


StE HFT: Hits per global track

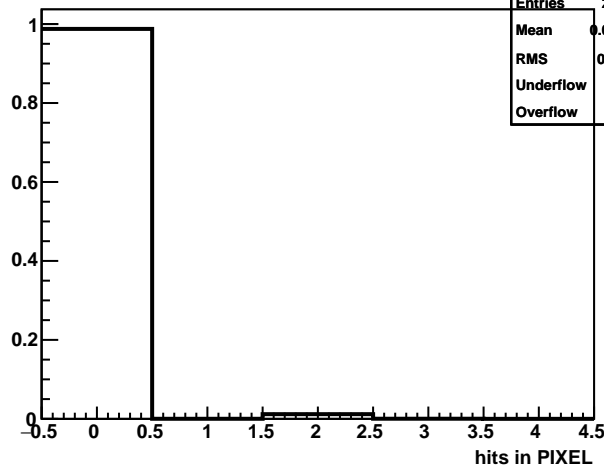
StEQaGrkHftHit	
Entries	900070
Mean	1.97
RMS	0.8144
Underflow	-1
Overflow	0



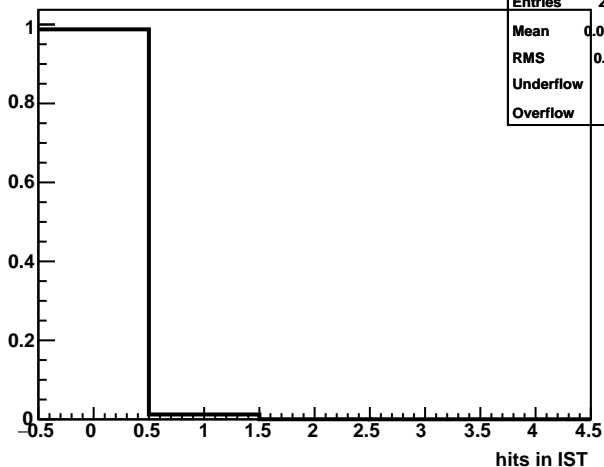
StE primtrk: N fit pnts on trk, tpc



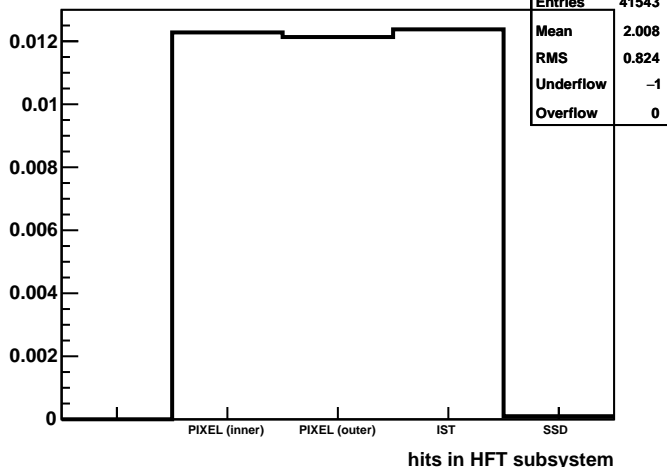
StE PIXEL: Hits per primary track



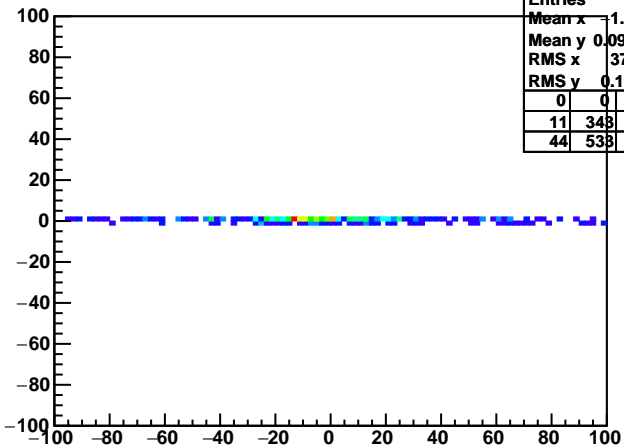
StE IST: Hits per primary track



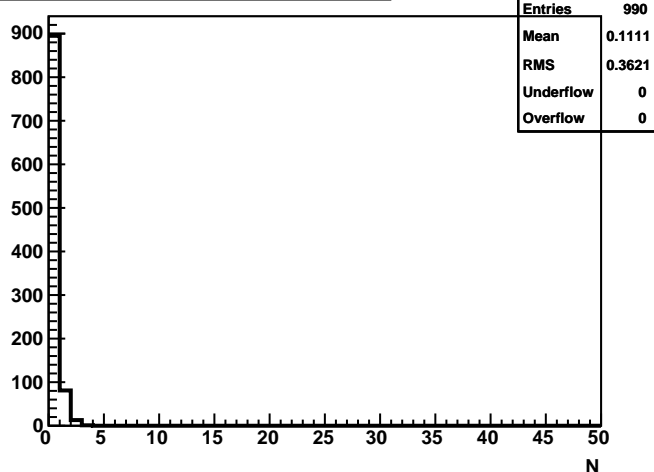
StE HFT: Hits per primary track

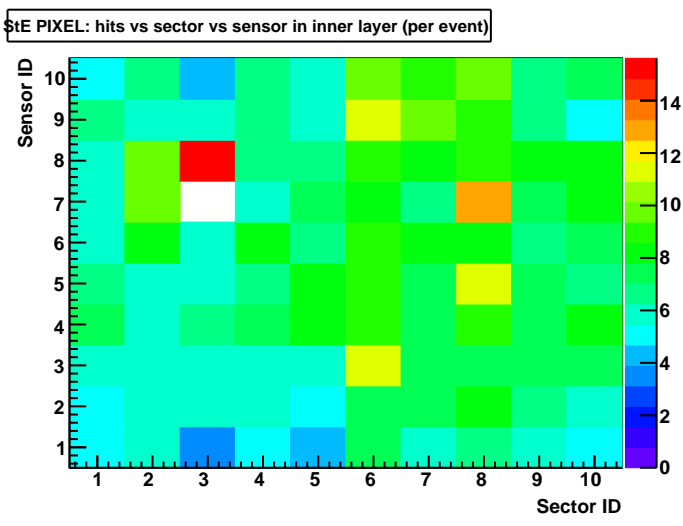
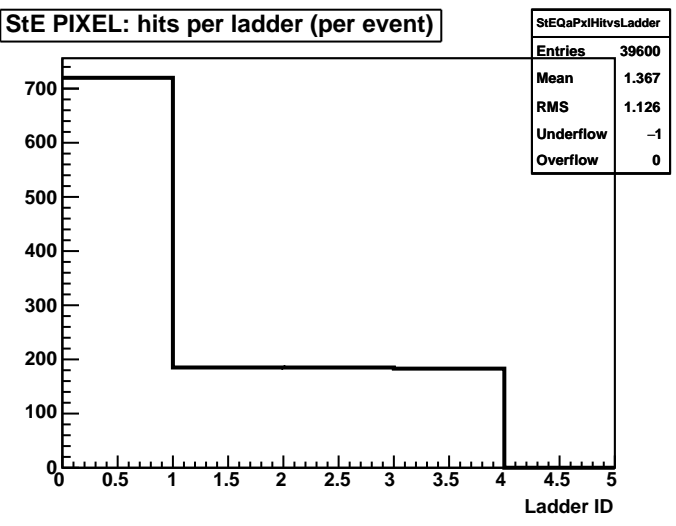
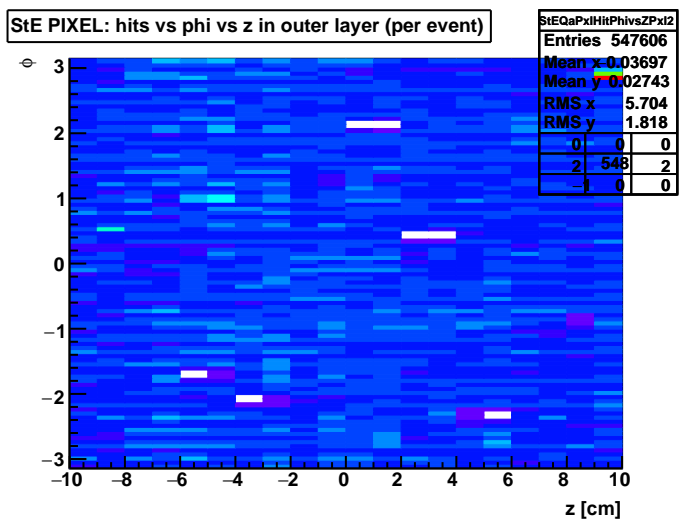
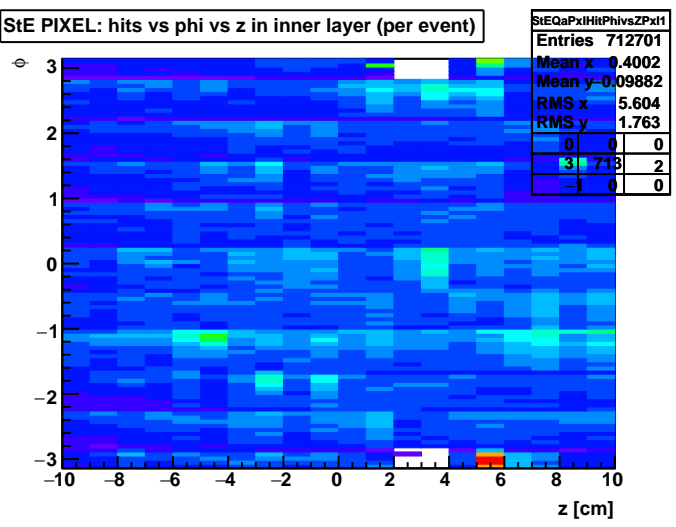
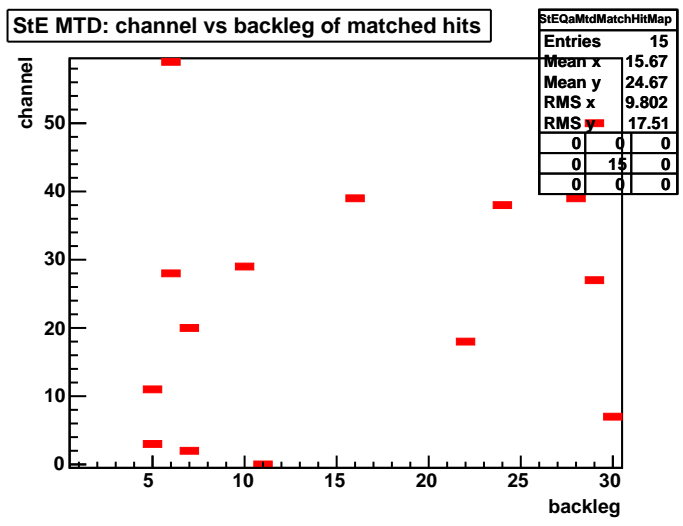
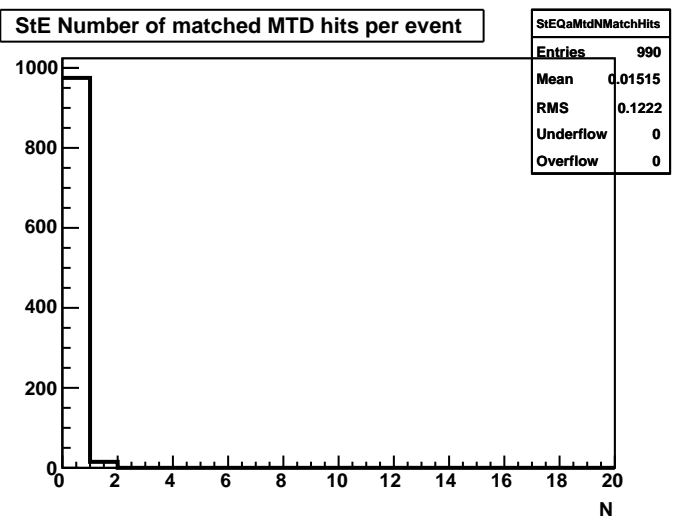


StE VPD vtx vs TPC vtx

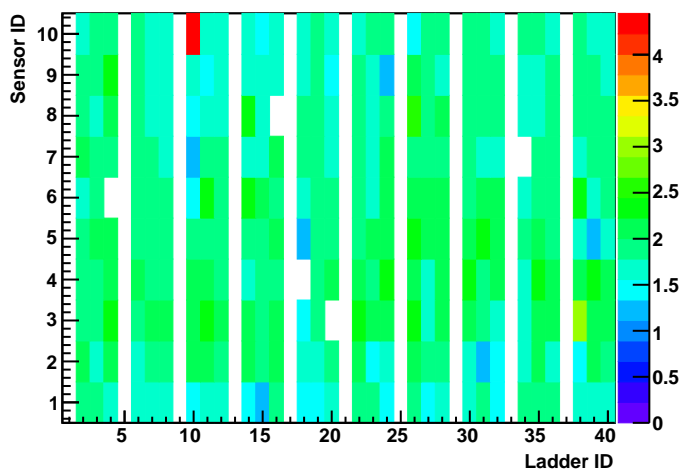


StE Number of MTD hits per event

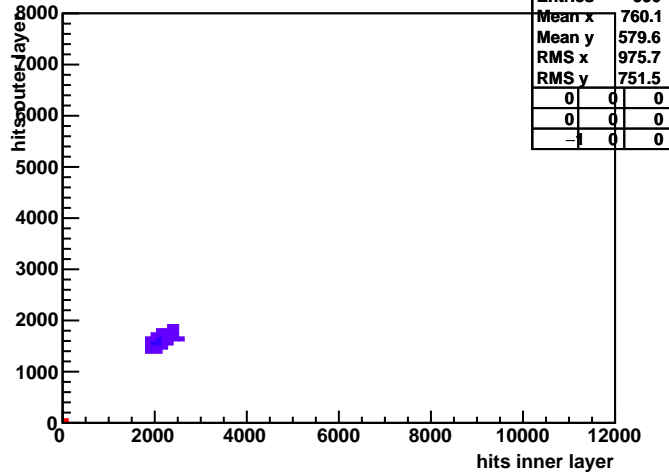




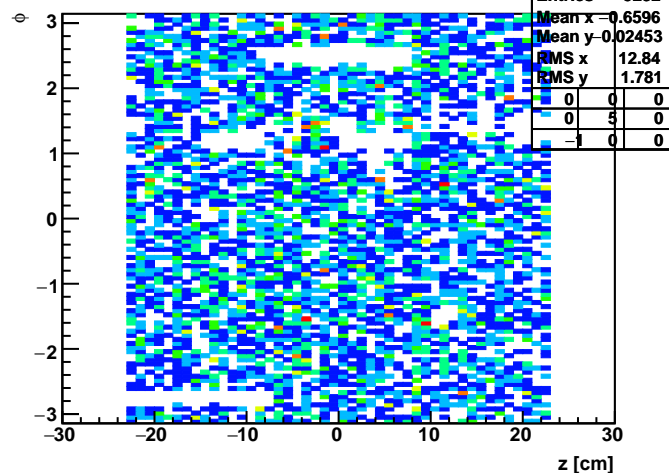
StE PIXEL: hits vs ladder vs sensor in outer layer (per event)



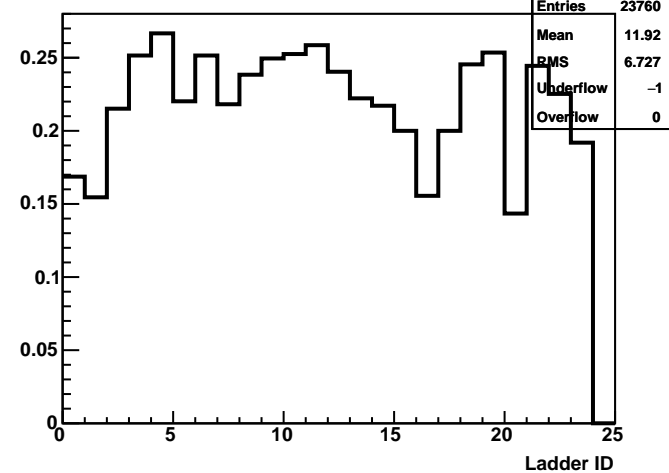
StE PIXEL: Hits in inner vs outer layer (per event)



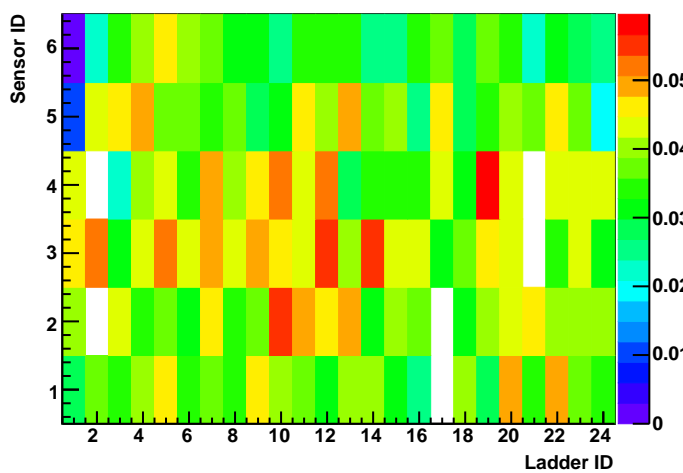
StE IST: Hits vs phi vs z (per event)



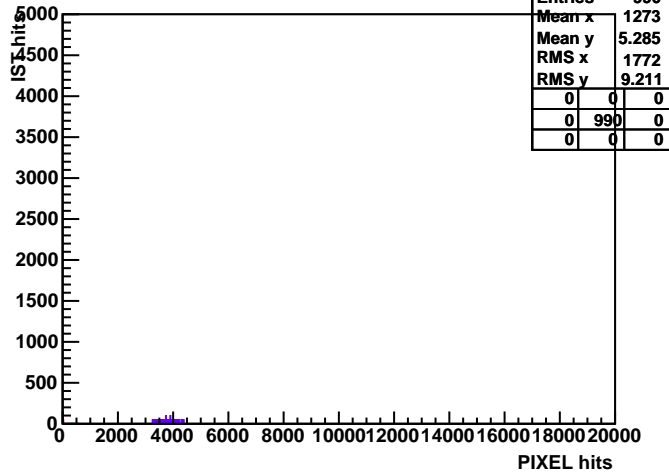
StE IST: Hits per ladder (per event)



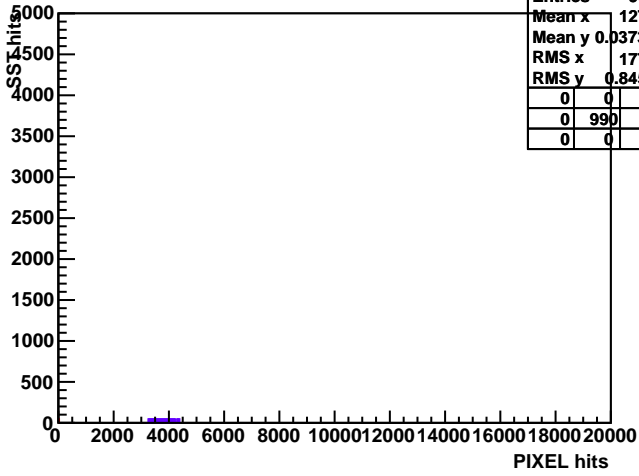
StE IST: Hits vs ladder vs sensor (per event)



StE PIXEL hits vs IST hits



StE PIXEL hits vs SST hits



StE IST hits vs SST hits

